

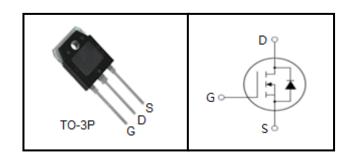
600V Super-Junction Power MOSFET

FEATURES

- $\bullet \quad \text{Very low FOM R}_{\text{DS(on)}} \times \text{Q}_{\text{g}} \\$
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)



Device Marking and Package Information			
Device	Package	Marking	
TPV60R095A	TO-3P	60R095A	

Absolute Maximum Ratings $T_C = 25^{\circ}C$, unless otherwise noted						
Dozomotov	Cumbal	Value	Unit			
Parameter	Symbol	TO-3P				
Drain-Source Voltage (V _{GS} = 0V)	V _{DSS}	600	V			
Continuous Drain Current	I _D	40	А			
Pulsed Drain Current (note1)	I _{DM}	120	А			
Gate-Source Voltage	V _{GSS}	±30	V			
Single Pulse Avalanche Energy (note2)	E _{AS}	720	mJ			
Avalanche Current (note1)	I _{AR}	12	А			
Repetitive Avalanche Energy (note1)	E _{AR}	1.5	mJ			
Power Dissipation (T _C = 25°C)	P _D	400	W			
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55~+150	°C			

Thermal Resistance					
Baramatar	O. male al	Value	l lmit		
Parameter	Symbol	TO-3P	Unit		
Thermal Resistance, Junction-to-Case	R _{thJC}	0.31	K/W		
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62			



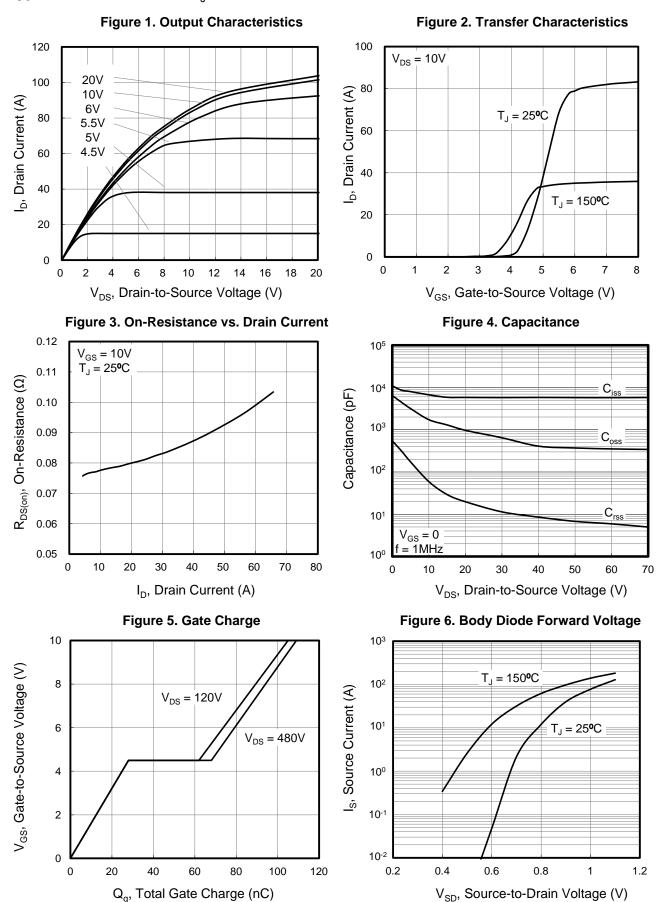
Parameter	Symbol	Test Conditions	Value			
			Min.	Тур.	Max.	Unit
Static		•				
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	600			V
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 600V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	μΑ
		$V_{DS} = 600V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			100	
Gate-Source Leakage	$I_{\rm GSS}$	$V_{GS} = \pm 30V$			±100	nA
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.0	V
Drain-Source On-Resistance (Note3)	R _{DS(on)}	V _{GS} = 10V, I _D = 20A		0.08	0.095	Ω
Forward Transconductance (Note3)	g _{fs}	V _{DS} = 10V, I _D = 20A		40		S
Dynamic						
Input Capacitance	C _{iss}	V 0V		5742		pF
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 50V,$		372		
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		6.8		
Total Gate Charge	Q_g			109		nC
Gate-Source Charge	Q_{gs}	$V_{DD} = 480V, I_{D} = 40A, V_{GS} = 10V$		28		
Gate-Drain Charge	Q_{gd}			40		
Turn-on Delay Time	t _{d(on)}			69.8		ns
Turn-on Rise Time	t _r	$V_{DD} = 400V, I_{D} = 40A,$		140		
Turn-off Delay Time	t _{d(off)}	$R_G = 25\Omega$		239		
Turn-off Fall Time	t _f			31		
Drain-Source Body Diode Characteris	stics					
Continuous Body Diode Current	I _s	T _C = 25°C			40	А
Pulsed Diode Forward Current	I _{SM}				120	
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 40A$, $V_{GS} = 0V$		0.95	1.2	V
Reverse Recovery Time	t _{rr}			528		ns
Reverse Recovery Charge	Q _{rr}	$V_R = 480V, I_F = I_S,$ $di_F/dt = 100A/\mu s$		7066		nC
Peak Reverse Recovery Current	I _{rrm}			27		Α

Notes

- 1. Repetitive Rating: Pulse Width limited by maximum junction temperature
- 2. I_{AS} = 12A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 1%



Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted





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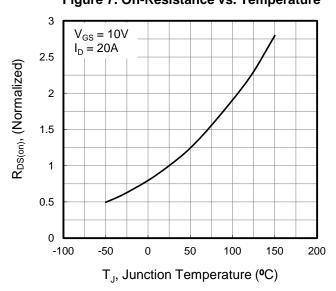


Figure 8. Threshold Voltage vs. Temperature

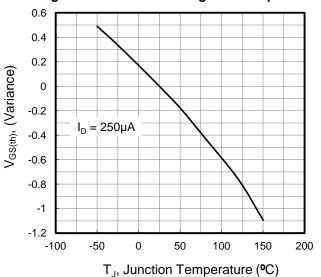


Figure 9. Transient Thermal Impedance

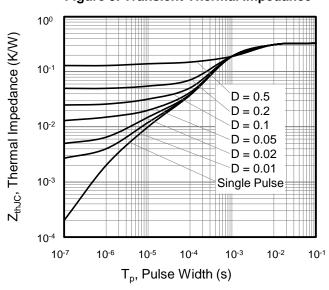


Figure 10. Safe Operating Area

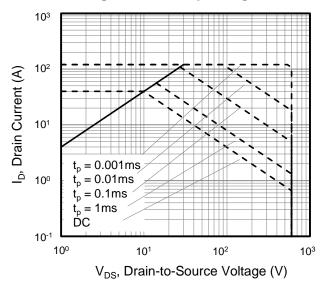




Figure A: Gate Charge Test Circuit and Waveform

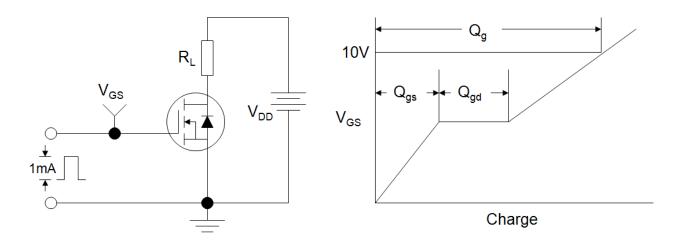


Figure B: Resistive Switching Test Circuit and Waveform

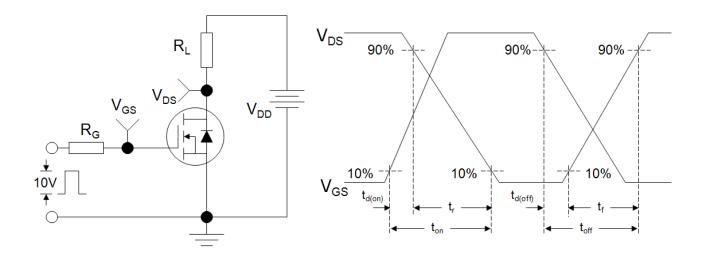
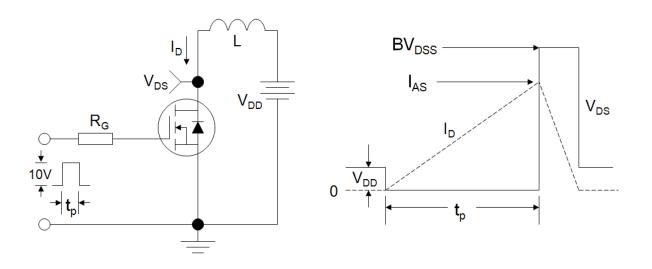


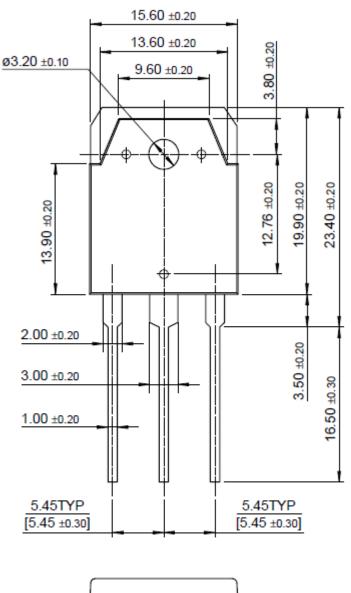
Figure C: Unclamped Inductive Switching Test Circuit and Waveform

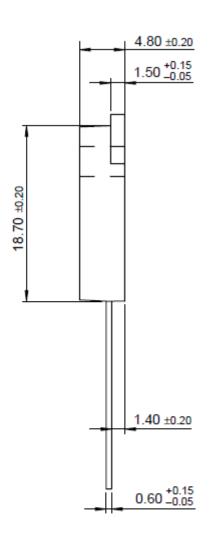






TO-3P







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